

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/597,472 HIRANO ET AL.	
		Examiner	Art Unit MARC A. SCHARICH	3611 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0045399	03-2005	Kudo et al.	180/219
*	B	US-2005/0126546	06-2005	Yagisawa, Katsuichi	123/509
*	C	US-2007/0023218	02-2007	Koike et al.	180/219
*	D	US-2007/0089713	04-2007	Koike et al.	123/509
*	E	US-2007/0216151	09-2007	Asamura et al.	280/833
*	F	US-2007/0240925	10-2007	Kobayashi, Manabu	180/219
*	G	US-2008/0011534	01-2008	MIYASHIRO, Shidehiko	180/219
*	H	US-2008/0314670	12-2008	Buell et al.	180/219
*	I	US-6,182,640	02-2001	Nakashima et al.	123/516
*	J	US-6,253,790	07-2001	Hara, Ikuo	137/565.17
*	K	US-6,401,750	06-2002	Tokunaga, Katsuhiko	137/565.34
*	L	US-7,275,523	10-2007	Kimura et al.	123/509
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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